

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/038,125	CHOE, GEON	
Examiner	Art Unit	
Angel A. Castro	2653	

SEARCHED					
Class	Subclass	Date	Examiner		
360	324.1, 324.11				
	324.1L				
29	(03.07, 603.2				
	603.13-603.16				
	603.18	6/23/05	AC		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST U.S. Pat: EPO, JPO	(/24/2-	0		
EPO, JPO	6/23/25	AC.		
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